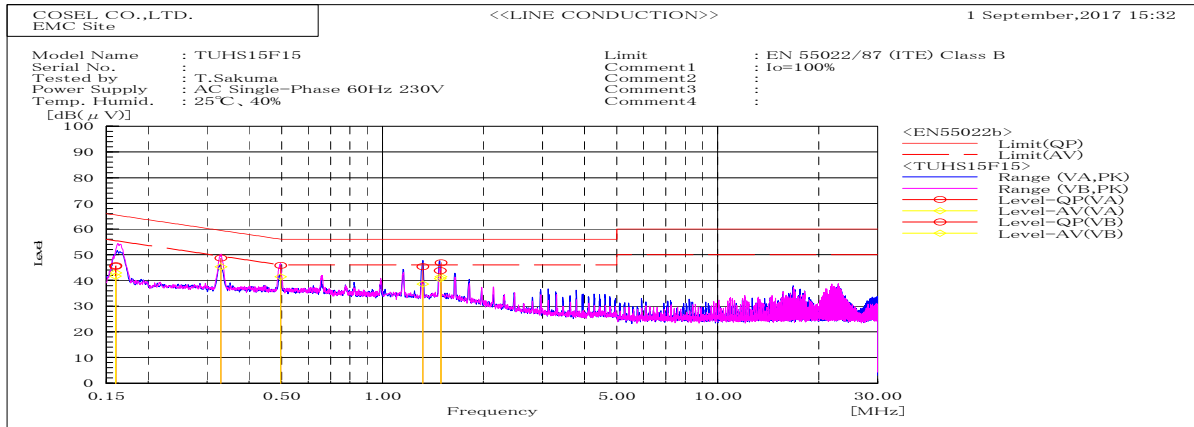
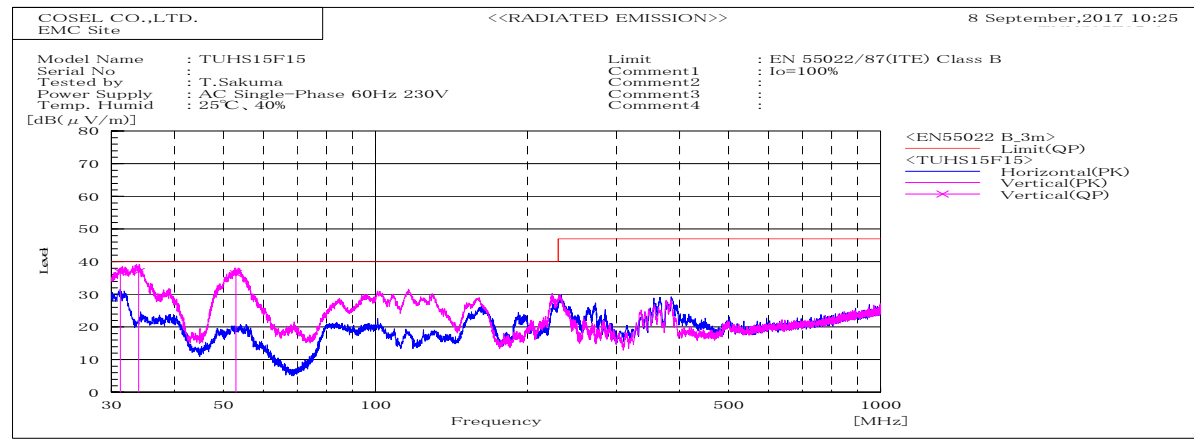


DATA SHEET		Date	13-Sep-17
Model	TUHS15F15	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma



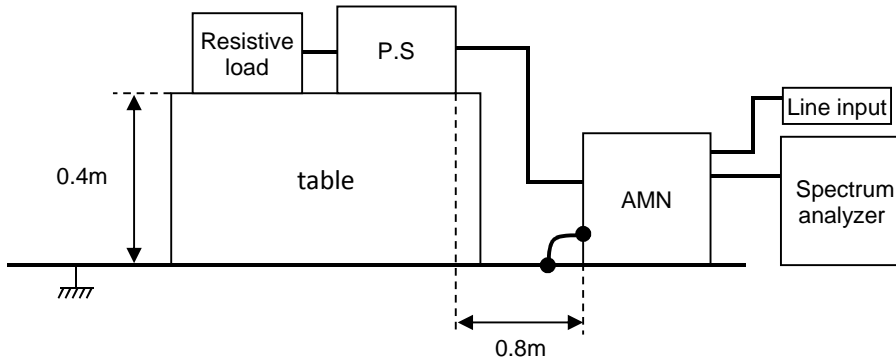
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV/m)		Limit dB(uV/m)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.16022		VA	24.7	22.0	21.0	45.7	43.0	65.5	55.5	19.8	12.5	Pass	
0.15973		VB	24.5	20.7	21.0	45.5	41.7	65.5	55.5	20.0	13.8	Pass	
0.32961		VB	27.8	24.4	20.9	48.7	45.3	59.5	49.5	10.8	4.2	Pass	
0.49692		VB	25.0	20.5	20.9	45.9	41.4	56.1	46.1	10.2	4.7	Pass	
1.31842		VA	24.4	17.6	21.0	45.4	38.6	56.0	46.0	10.6	7.4	Pass	
1.49388		VA	25.9	20.4	21.0	46.9	41.4	56.0	46.0	9.1	4.6	Pass	
1.4869		VB	22.8	19.7	21.0	43.8	40.7	56.0	46.0	12.2	5.3	Pass	



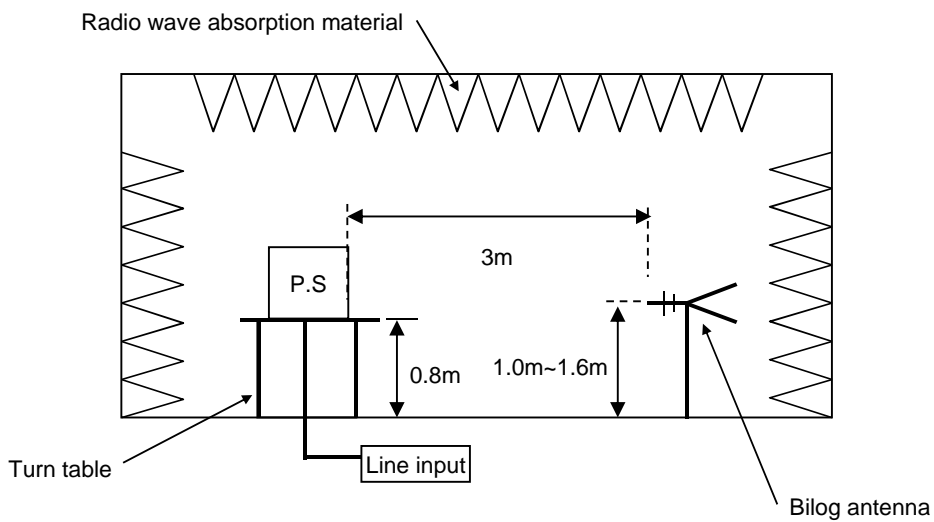
Frequency MHz	Polarization	Stability	Reading dB(uV)	Factor dB(1/m)	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
31.250	V	Stable	46.5	-9.7	36.8	40.0	3.2	Pass	101	1	
33.958	V	Stable	46.8	-9.8	37.0	40.0	3.0	Pass	105	49	
52.892	V	Stable	56.9	-20.5	36.4	40.0	3.6	Pass	119	354	

DATA SHEET		Date	13-Sep-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma

1. Line conduction



2. Radiated emission

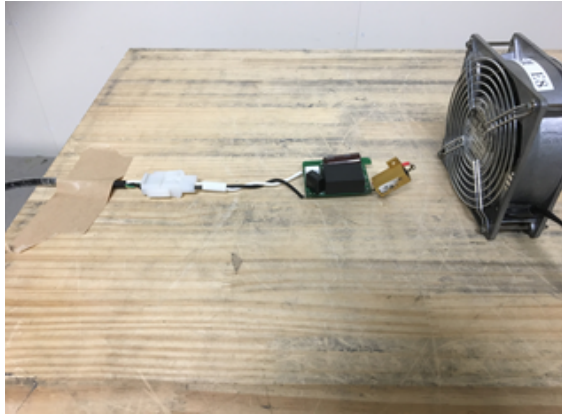


Conditions

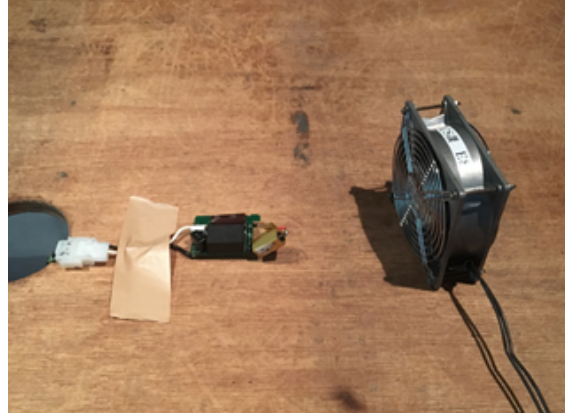
Test: EMI
 Model Name: TUHS15F15

- Photographs of Test Set-Up

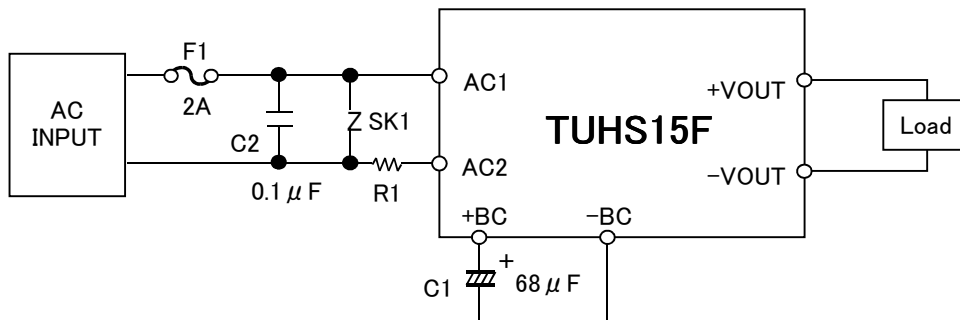
LINE CONDUCTION



RADIATED EMISSION



- Test circuit



- | | | |
|------|---------------------------|------|
| F1: | SLT250V2A (Nippon Seisen) | 2A |
| R1: | CW3CJ (KOA) | 10 Ω |
| SK1: | S10K385E2K1 (TDK EPCOS) | |

Fig.1 Testing circuitry